



# 26<sup>th</sup> IEEE European Test Symposium

Virtual Interactive Event

May 24 – 28, 2021, Belgium



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The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, hot topics, and new trends, industrial case-studies and applications, in the area of electronic-based circuits and system testing, reliability, safety, security and validation. The 2021 edition of ETS will be a virtual one. The organizing team will strive to keep the spirit of ETS alive, by organizing an event with live sessions and many opportunities for networking and peer interaction. ETS'21 is organized jointly by imec and KU Leuven, which co-sponsor the event together with the IEEE Council on Electronic Design Automation (CEDA).

The program includes keynotes, scientific paper presentations, panels, tutorials, workshops and highlights/demos from industry. Besides regular technical papers, ETS'21 provides the opportunity of submitting scientific contributions for hot-topic papers and case-study papers (each with specific evaluation criteria). Submissions are also solicited for special sessions, panels, tutorials and workshops, as well as for the PhD Forum. Linked to the main ETS'21 symposium, the Test Spring School and Fringe Workshops will be organized.

You are invited to participate and submit your contributions to ETS'21. The areas of interest include (but are not limited to) the following topics:

- Analog, Mixed-Signal and RF Test
- Approximate Circuit Testing
- ATE Hardware and Software
- Automatic Test Generation
- Automotive and Avionics Test
- Board Test and Diagnosis
- Built-In Self-Test
- Current-Based Test
- Defect-Based Test
- Delay and Performance Test
- Dependability and Functional Safety
- Design for Test
- DfX (Design for Manufacturing, Reliability, Yield, etc.)
- Diagnosis and Silicon Debug
- Economics of Test
- Failure Analysis
- Fault Modeling and Simulation
- Fault Tolerance
- Hardware Security
- Hardware Trust
- High-Speed I/O Test
- Low-Power Test
- Machine Learning and AI for Test
- Memory Test and Repair
- Microsystems / MEMS / Sensors Test
- On-Line Test
- Power / Thermal-Aware Test
- Processor Test (Multi-Core, GPU, CPU, Neuromorphic, etc.)
- Security Issues in Test
- Self-X (Awareness, Repair, Test, etc.)
- Signal Integrity Test
- SoC and NoC Test
- Stacked or 3D ICs Test
- Standards in Test
- Test of Reconfigurable Systems (FPGA, CPLD, etc.)
- Test, Reliability and Security of Emerging Technologies
- Test, Reliability and Security of Emerging Computing (Neuromorphic, In-Memory, Reversible and Quantum Circuits, etc.)
- Trojan Detection
- Verification and Validation
- Yield Analysis and Enhancement

**Submissions:** ETS'21 seeks original, unpublished contributions of the following types:

- **Scientific Papers** for the Formal Proceedings:
  - **Regular Papers**, presenting novel and complete research work
  - **Hot-Topic Papers**, presenting early innovative ideas with in-progress results, emerging and future test/reliability/safety problems, or identifying open problems that merit innovative future research
  - **Case-Study Papers**, presenting relevant industrial (or industrial collaboration) data that demonstrate a previously published concept, or that can help further research advancements.
- **PhD Forum Contributions** from students eager to discuss their on-going research.
- **Proposals for Panels, Embedded Tutorials, Special Sessions and Fringe Workshops.**
- **Industrial Presentations and Demos** focusing on new features of test/reliability/safety-related products.

**Publications:** ETS'21 will produce Formal Proceedings of scientific papers with ISBN number that will be included in the IEEE Xplore Digital Library. All accepted technical papers submitted in one of the three categories (regular, hot topic, and case study) will be included in the formal Proceedings (each following its own guidelines). Extended versions of selected papers will be invited for submission in an IEEE Journal Special Issue dedicated to ETS'21.

## Key Dates for Submissions:

<b>Scientific Papers: Title and abstract</b>	<b>December 10<sup>th</sup>, 2020</b>
Full Paper	<b>December 17<sup>th</sup>, 2020</b>
<b>PhD Forum, panels, tutorials and special sessions:</b>	
<b>Fringe Workshops:</b>	<b>January 22<sup>nd</sup>, 2021</b>
<b>Notification of acceptance:</b>	<b>November 30<sup>th</sup>, 2020</b>
<b>Camera-ready manuscript:</b>	<b>February 12<sup>th</sup>, 2021</b>
	<b>March 15<sup>th</sup>, 2021</b>

## Further Information:

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